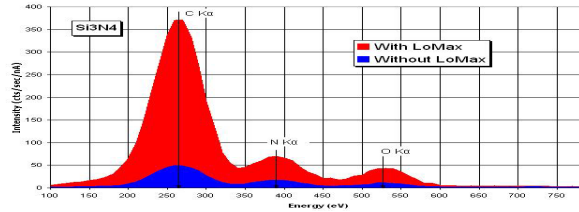


JoeXray LLC



Hello,

I would like to introduce you to myself and to some exciting new products available to enhance your X-ray Microanalysis.

My name is Joe Ullmer, you may have known me from the past as I worked for various EDS manufacturers from 1984 to 2007.

I now have my own representative company, JoeXray LLC, and I represent Parallax Research. Parallax has been designing and manufacturing the focused optics used by various instrument manufacturers since 1995.

The most recent advances are only available from Parallax and consist of the following:

LoMax - This product is a focused optic that replaces the collimator on most SEM EDS detectors, regardless of the original manufacturer. This optic increases the light element response up to 10x to allow for increased sensitivity and faster mapping and linescans of the elements being attenuated. Optics may be interchanged to increase response of virtually any element or elemental range with this tool.

HEXS - The HEXS is the latest design and most complete Parallel Beam Wavelength Dispersive Spectrometer system available. The latest 5 cone optic set, upgrade to 6 diffractors in place of 5, additional internal optics, and the latest WDS detection and counting electronics insure the best PBS detection. There is no need for poly-capillaries or positioning devices, and this system does not lack the necessary energy range.

PRISM - By combining the latest 4pi RevolutionEDX™ system with your choice of Si(Li) or Silicon-Drift X-ray detector and the Parallax HEXS Parallel Beam WDS system you have the highest performance SEM X-ray Microanalysis system on the market. Add the LoMax EDS optic to insure that you do obtain the highest level of analysis in the world, at a price well below any other comparable package!

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